Low-Bias Correction Energy

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- Electrons fired perpendicular to calorimeter
- Data generated with 60 thin layers
- Model undersampling of deep layers by ignoring data from alternate silicon layers
 - Thin layer $\approx 0.64 X_0$
 - Thick layer $\approx 1.28 X_0$
- Correction methods here use only 16 thin layers and 8 thick layers to measure energy and make correction
 - SiD uses 20 thin and 10 thick layers

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Correction Energy from Last Six Layers

- Correlate ratio of energy lost to energy measured
- Function of EL6/E32
- Trend consistent across particle energies
- · Model trained on one particle energy can correct other energies



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- One hidden layer
- Batch size = 32
- Epochs = 1000
- Train on each data set separately
- Weight each fit based on how close a given particle's energy deposition is to the average deposited by each training set: [Law - Lav]¹⁰
 - Eavg is average energy deposited by each training set
 - E32 is the energy deposited for the event being corrected

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Examples of Neural Network Performance using Discrete Particle Energies

Measured, Corrected, Ideal



Histogram of 100GeV Events Trained with a Neural Network (1 Hidden Layer) - 16+8 Layers (Under-sampled)





Histogram of 50GeV Events Trained with a Neural Network (1 Hidden Layer) - 16+8 Layers (Under-sampled)

Histogram of 150GeV Events Trained with a Neural Network (1 Hidden Layer) - 16+8 Layers (Under-sampled)



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- Neural network trained on entire distribution
- When correcting continuous distribution, resolution calculated by dividing distribution into bins with equal numbers of events



Each event is scaled by $\sqrt{E_{Truth}}$ and divided by $\sqrt{<E_{Truth}>}$ after binning to improve accuracy of resolution



Measured, Corrected, Ideal

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NN Trained on Continuous Distribution Correcting Continuous Particle Energy Distribution

Measured, Corrected, Ideal



NN Trained on Continuous Distribution Correcting Continuous Particle Energy Distribution

Measured, Corrected, Ideal





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NN Trained on Angle Distribution at Constant Energy

- \bullet Electrons incident at random angles between 0° and 50°
- Constant energy: 100GeV



NN Trained on Angle Distribution at Constant Energy

Measured, Corrected, Ideal



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NN Trained on Angle Distribution at Constant Energy

Measured, Corrected, Ideal



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Comparison of Angle Distribution and Energy Distribution Training



 $\bullet~100 GeV$ events at 30°

 Correction using energy distribution (20-300GeV) at 30° works slightly better than angle distribution (0°-50°) at 100GeV

100GeV at 30° Trained with a Neural Network (8 Hidden Lavers, Angle Distribution) (Under-sampled) - 16+8 Lavers



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Measured, Corrected, Ideal

NN Trained on Angle and Energy Distribution

• 10000 events, 20-300GeV, $0^\circ\text{--}50^\circ$



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NN Trained on Angle and Energy Distribution

Measured, Corrected, Ideal



Scaled Deviation from True Energy (MeV3/2)



244GeV to 299GeV at 39°-49° Trained with a Neural Network (1 Hidden Laver) - (Under-sampled) 16+8 Lavers



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Large resolution improvement at shallow angles Resolution improvement less important at steep angles



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Full SiD Model

- More thorough geometry model
- Modified SiD specifications:
 - No solenoid, B = 0
 - No vertex detector, tracker, HCal, or muon system
 - Extended ECal to 60 layers
- Tested NN on distribution of energies (20-300GeV) and angles ($\theta \in (0^{\circ}, 45^{\circ})$, $\phi \in (0^{\circ}, 360^{\circ})$)



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Measured, Corrected, Ideal







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- Account of geometry complications
 - $\bullet\,$ Overlapping regions in ϕ
- Increase amount of data used in NN
 - Number of hits per layer
 - Consider ϕ in analysis as well as θ
- Use ECal hits to calculate angle of incidence (instead of MC truth)

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